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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Rainer Bruchhaus et al. Art Unit: 2811  
Serial No.: 10/673,053 Examiner:  
Filed : September 26, 2003  
Title : PROCESS FOR FABRICATION OF A FERROCAPACITOR

**Mail Stop Amendment**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants call attention to the attached Information Disclosure Statement and documents listed on form PTO-1449.

This filing is being made before the receipt of a first Office action on the merits. No fee is required.

Each enclosed document listed on the herewith Form PTO-1449 was cited in the attached International Search Report dated December 27, 2004, issued in a foreign counterpart application. To the best knowledge of the undersigned, this is the first citation of these items in any communication from a foreign patent office in a counterpart foreign application.

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Applicant : Rainer Bruchhaus et al.  
Serial No.: 10/673,053  
Filed : September 26, 2003  
Page 2 of 2

Attorney's Docket No.:14580-031001

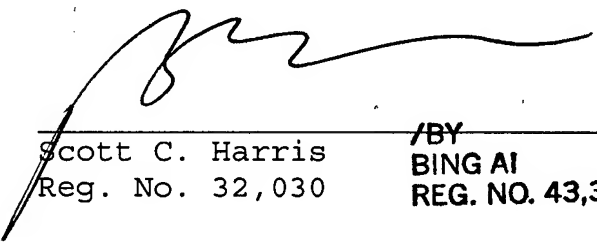
The documents are in the English language; hence no concise explanation is necessary per Rule 98(a)(3).

Consideration of the foregoing and enclosures plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

Please apply any additional charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

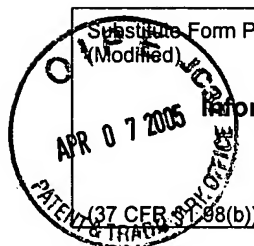
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 Substitute Form PTO-1449  
 (Modified)

 U.S. Department of Commerce  
 Patent and Trademark Office

 Attorney's Docket No.  
 14580-031001

 Application No.  
 10/673,053

**Information Disclosure Statement  
 by Applicant**

(Use several sheets if necessary)

 Applicant  
 Rainer Bruchhaus et al.

 Filing Date  
 September 26, 2003

 Group Art Unit  
 2811

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2001/0007366	07/2001	Kim, et al.			
	AB	2002/0163058	11/2002	Chen, et al.			
	AC	2003/0058700	03/2003	Bruchhaus, et al.			
	AD	2003/0175487	09/2003	Kita			
	AE	5,155,573	10/1992	Abe, et al.			
	AF	5,745,336	04/1998	Saito, et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AP	Katsuhiro Aoki, et al., "Effects of Titanium Buffer Layer on Lead-Zirconate-Titanate Crystallization Processes in Sol-Gel Deposition Technique", <i>Jpn. J. Appl. Phys.</i> , Vol. 34, Part 1, No. 1, pp. 192-195, Jan. 1995.
	AQ	Katsuhiro Aoki, et al., "Ferroelectric Properties of Crystalline-Oriented Lead-Zirconate-Titanates Formed by Sol-Gel Deposition Technique", <i>Jpn. J. Appl. Phys.</i> , Vol. 34, Part 1, No. 2B, pp. 746-751, Feb. 1995.
	AR	P. Muralt, et al., "Texture control of PbTiO <sub>3</sub> and Pb(Zr, Ti)O <sub>3</sub> thin films with TiO <sub>2</sub> seeding", <i>J. Appl. Physics</i> , 83(7):3835-3841, April 1998.
	AS	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.